

Subject card

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Subject name and code	, PG_00052090								
Field of study	Nanotechnology								
Date of commencement of studies	October 2020		Academic year of realisation of subject			2022/2023			
Education level	first-cycle studies		Subject group			Optional subject group Subject group related to scientific research in the field of study			
Mode of study	Full-time studies		Mode of delivery			at the university			
Year of study	3		Language of instruction			Polish			
Semester of study	6		ECTS credits			4.0			
Learning profile	general academic profile		Assessment form			assessment			
Conducting unit	Zakład nowych materiałów funkcjonalnych do konwersji energii -> Instytu Materiałowej -> Faculty of Applied Physics and Mathematics				Instytu	t Nanotechnologii i Inżynierii			
Name and surname	Subject supervisor		dr hab. inż. Jakub Karczewski						
of lecturer (lecturers)	Teachers		dr hab. inż. Jakub Karczewski						
Lesson types and methods	Lesson type	Lecture	Tutorial	Laboratory	Projec	t	Seminar	SUM	
of instruction	Number of study hours	15.0	0.0	15.0	15.0		0.0	45	
	E-learning hours inclu	learning hours included: 0.0			•				
Learning activity and number of study hours	Learning activity	Participation in classes include plan		Participation in consultation hours		Self-study		SUM	
	Number of study 45 hours			6.0		49.0		100	
Subject objectives	Learning about modern methods of imaging nanostructures.								
Learning outcomes	Course outcome Subject outcome Method of verification								
	K6_U04		The student is able to prepare, perform and interpret an experiment in the field of modern imaging methods.			[SU4] Assessment of ability to use methods and tools [SU3] Assessment of ability to use knowledge gained from the subject [SU2] Assessment of ability to analyse information			
	K6_W10		The student is able to prepare, perform and interpret an experiment in the field of modern imaging methods.			[SW1] Assessment of factual knowledge			
	K6_K04					[SK1] Assessment of group work skills			
	K6_W09		The student knows and understands the principles of operation, is able to perform measurements using SEM, AFM, STM microscopy.		[SW1] Assessment of factual knowledge				
Subject contents	optical microscopy tunnel microscopy atomic force microscopy scanning electron microscopy transmission electron microscopy								
Prerequisites and co-requisites	basic knowledge of physics								
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Assessment methods	Subject passing criteria	Passing threshold	Percentage of the final grade			
and criteria	presentation of the results of laboratory work	50.0%	50.0%			
	lecture exam	50.0%	50.0%			
Recommended reading	Basic literature	Weilie Zhou Zhong Lin Wang "Scanning Microscopy for Nanotechnology Techniques and Applications"V. L. Mironov "Fundamentals of Scanning Probe Microscopy"				
	Supplementary literature	Nanosurf easyScan 2 - operating instruction				
	eResources addresses	Adresy na platformie eNauczanie:				
		Metody mikroskopowe w nanotechnologii - Moodle ID: 30230 https://enauczanie.pg.edu.pl/moodle/course/view.php?id=30230				
Example issues/ example questions/ tasks being completed						
Work placement	Not applicable					

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